

## 54ABT/74ABT543

### Octal Registered Transceiver with TRI-STATE® Outputs

#### General Description

The 54ABT543 octal transceiver contains two sets of D-type latches for temporary storage of data flowing in either direction. Separate Latch Enable and Output Enable inputs are provided for each register to permit independent control of inputting and outputting in either direction of data flow.

#### Features

- Back-to-back registers for storage
- Bidirectional data path
- A and B outputs have current sourcing capability of 32 mA and current sinking capability of 64 mA

- Separate controls for data flow in each direction
- Guaranteed output skew
- Guaranteed multiple output switching specifications
- Output switching specified for both 50 pF and 250 pF loads
- Guaranteed simultaneous switching noise level and dynamic threshold performance
- Guaranteed latchup protection
- High impedance glitch free bus loading during entire power up and power down cycle
- Nondestructive hot insertion capability
- Standard Military Drawing (SMD) 5962-9231401

#### Ordering Code: See Section 10

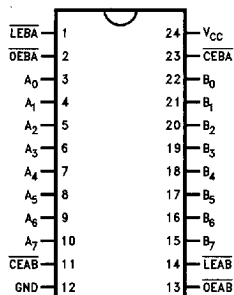
Commercial	Military	Package Number	Package Description
74ABT543CSC (Note 1)		M24B	24-Lead (0.300" Wide) Molded Small Outline, JEDEC
	54ABT543J/883	J24A	24-Lead Ceramic Dual-In-Line
74ABT543CMSA (Note 1)		MSA24	24-Lead Molded Shrink Small Outline, EIAJ Type II
	54ABT543W/883	W24C	24-Lead Cerpack
	54ABT543E/883	E28A	28-Lead Ceramic Leadless Chip Carrier, Type C
74ABT543CMT (Notes 1, 2)		MTC24	24-Lead Molded Thin Shrink Small Outline, JEDEC

Note 1: Devices also available in 13" reel. Use suffix = SCX, MSAX and MTCX.

Note 2: Contact factory for package availability.

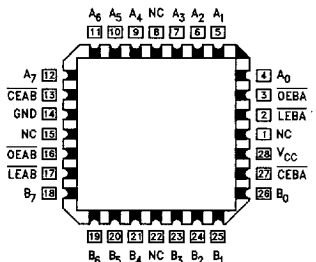
#### Connection Diagrams

Pin Assignment for  
DIP, SOIC, SSOP and Flatpak



TL/F/11508-1

Pin Assignment  
for LCC



TL/F/11508-2

#### Pin Descriptions

Pin Names	Description
OEAB, OEBA	Output Enable Inputs
LEAB, LEBA	Latch Enable Inputs
CEAB, CEBA	Chip Enable Inputs
A0-A7	Side A Inputs or TRI-STATE Outputs
B0-B7	Side B Inputs or TRI-STATE Outputs

## Functional Description

The 'ABT543 contains two sets of D-type latches, with separate input and output controls for each. For data flow from A to B, for example, the A to B Enable ( $\overline{CEAB}$ ) input must be low in order to enter data from the A port or take data from the B port as indicated in the Data I/O Control Table. With  $\overline{CEAB}$  low, a low signal on ( $\overline{LEAB}$ ) input makes the A to B latches transparent; a subsequent low to high transition of the  $\overline{LEAB}$  line puts the A latches in the storage mode and their outputs no longer change with the A inputs. With  $\overline{CEAB}$  and  $\overline{OEAB}$  both low, the B output buffers are active and reflect the data present on the output of the A latches. Control of data flow from B to A is similar, but using the  $\overline{CEBA}$ ,  $\overline{LEBA}$  and  $\overline{OEBA}$ .

Data I/O Control Table

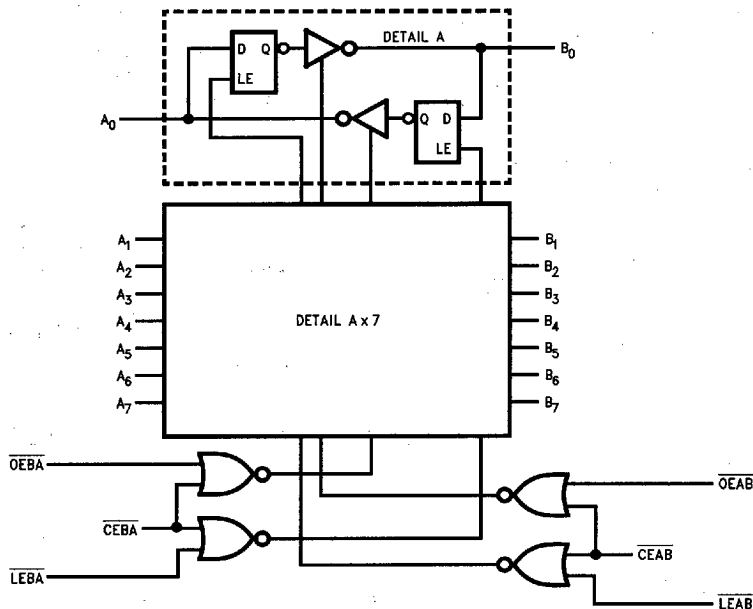
Inputs			Latch Status	Output Buffers
$\overline{CEAB}$	$\overline{LEAB}$	$\overline{OEAB}$		
H	X	X	Latched	High Z
X	H	X	Latched	—
L	L	X	Transparent	—
X	X	H	—	High Z
L	X	L	—	Driving

H = High Voltage Level

L = Low Voltage Level

X = Immaterial

## Logic Diagram



TL/F/11508-3

## Absolute Maximum Ratings (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

Storage Temperature	−65°C to +150°C
Ambient Temperature under Bias	−55°C to +125°C
Junction Temperature under Bias	
Ceramic	−55°C to +175°C
Plastic	−55°C to +150°C
V <sub>CC</sub> Pin Potential to Ground Pin	−0.5V to +7.0V
Input Voltage (Note 2)	−0.5V to +7.0V
Input Current (Note 2)	−30 mA to +5.0 mA
Voltage Applied to Any Output in the Disable or Power-Off State in the HIGH State	−0.5V to +5.5V −0.5V to V <sub>CC</sub>

**Note 1:** Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

**Note 2:** Either voltage limit or current limit is sufficient to protect inputs.

Current Applied to Output in LOW State (Max)	twice the rated I <sub>OL</sub> (mA)
DC Latchup Source Current	−500 mA
Over Voltage Latchup (I/O)	10V

## Recommended Operating Conditions

Free Air Ambient Temperature	
Military	−55°C to +125°C
Commercial	−40°C to +85°C
Supply Voltage	
Military	+4.5V to +5.5V
Commercial	+4.5V to +5.5V
Minimum Input Edge Rate	( $\Delta V/\Delta t$ )
Data Input	50 mV/ns
Enable Input	20 mV/ns
Clock Input	100 mV/ns

## DC Electrical Characteristics

Symbol	Parameter	ABT543			Units	V <sub>CC</sub>	Conditions
		Min	Typ	Max			
V <sub>IH</sub>	Input HIGH Voltage	2.0			V		Recognized HIGH Signal
V <sub>IL</sub>	Input LOW Voltage			0.8	V		Recognized LOW Signal
V <sub>CD</sub>	Input Clamp Diode Voltage			−1.2	V	Min	I <sub>IN</sub> = −18 mA (Non I/O Pins)
V <sub>OH</sub>	Output HIGH Voltage 54ABT/74ABT	2.5			V	Min	I <sub>OH</sub> = −3 mA, (A <sub>n</sub> , B <sub>n</sub> )
		2.0					I <sub>OH</sub> = −24 mA, (A <sub>n</sub> , B <sub>n</sub> )
		2.0					I <sub>OH</sub> = −32 mA, (A <sub>n</sub> , B <sub>n</sub> )
V <sub>OL</sub>	Output LOW Voltage 54ABT/74ABT			0.55	V	Min	I <sub>OL</sub> = 48 mA, (A <sub>n</sub> , B <sub>n</sub> )
				0.55			I <sub>OL</sub> = 64 mA, (A <sub>n</sub> , B <sub>n</sub> )
V <sub>ID</sub>	Input Leakage Test	4.75			V	0.0	I <sub>ID</sub> = 1.9 $\mu$ A, (Non-I/O Pins) All Other Pins Grounded
I <sub>IH</sub>	Input HIGH Current			5	$\mu$ A	Max	V <sub>IN</sub> = 2.7V (Non-I/O Pins) (Note 3) V <sub>IN</sub> = V <sub>CC</sub> (Non-I/O Pins)
I <sub>BVI</sub>	Input HIGH Current Breakdown Test			7	$\mu$ A	Max	V <sub>IN</sub> = 7.0V (Non-I/O Pins)
I <sub>BVIT</sub>	Input HIGH Current Breakdown Test (I/O)			100	$\mu$ A	Max	V <sub>IN</sub> = 5.5V (A <sub>n</sub> , B <sub>n</sub> )
I <sub>IL</sub>	Input LOW Current			−5	$\mu$ A	Max	V <sub>IN</sub> = 0.5V (Non-I/O Pins) (Note 3) V <sub>IN</sub> = 0.0V (Non-I/O Pins)
I <sub>IH</sub> + I <sub>OZH</sub>	Output Leakage Current			50	$\mu$ A	0V–5.5V	V <sub>OUT</sub> = 2.7V (A <sub>n</sub> , B <sub>n</sub> ); OEAB or CEAB = 2V
I <sub>IL</sub> + I <sub>OZL</sub>	Output Leakage Current			−50	$\mu$ A	0V–5.5V	V <sub>OUT</sub> = 0.5V (A <sub>n</sub> , B <sub>n</sub> ); OEAB or CEAB = 2V
I <sub>OS</sub>	Output Short-Circuit Current	−100	−275		mA	Max	V <sub>OUT</sub> = 0V (A <sub>n</sub> , B <sub>n</sub> )
I <sub>CEX</sub>	Output HIGH Leakage Current			50	$\mu$ A	Max	V <sub>OUT</sub> = V <sub>CC</sub> (A <sub>n</sub> , B <sub>n</sub> )
I <sub>ZZ</sub>	Bus Drainage Test			100	$\mu$ A	0.0V	V <sub>OUT</sub> = 5.5V (A <sub>n</sub> , B <sub>n</sub> ); All Others GND
I <sub>QCH</sub>	Power Supply Current			50	$\mu$ A	Max	All Outputs HIGH
I <sub>QCL</sub>	Power Supply Current			30	mA	Max	All Outputs LOW
I <sub>CCZ</sub>	Power Supply Current			50	$\mu$ A	Max	Outputs TRI-STATE All Others at V <sub>CC</sub> or GND

**Note 3:** Guaranteed but not tested.

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## DC Electrical Characteristics (Continued)

Symbol	Parameter	ABT543			Units	V <sub>CC</sub>	Conditions
		Min	Typ	Max			
I <sub>CCT</sub>	Additional I <sub>CC</sub> /Input			2.5	mA	Max	V <sub>I</sub> = V <sub>CC</sub> - 2.1V All Others at V <sub>CC</sub> or GND
I <sub>CCD</sub>	Dynamic I <sub>CC</sub> No Load (Note 2)			0.18	mA/MHz	Max	Outputs Open, $\overline{\text{CEAB}}$ and $\overline{\text{OEAB}}$ = GND, $\overline{\text{CEBA}}$ = V <sub>CC</sub> , One Bit Toggling, 50% Duty Cycle, (Note 1)

**Note 1:** For 8-bit toggling, I<sub>CCD</sub> < 1.4 mA/MHz.

**Note 2:** Guaranteed, but not tested.

## DC Electrical Characteristics (SOIC Package)

Symbol	Parameter	Min	Typ	Max	Units	V <sub>CC</sub>	Conditions C <sub>L</sub> = 50 pF, R <sub>L</sub> = 500Ω
V <sub>OLP</sub>	Quiet Output Maximum Dynamic V <sub>OL</sub>		0.7	1.0	V	5.0	T <sub>A</sub> = 25°C (Note 1)
V <sub>OLV</sub>	Quiet Output Minimum Dynamic V <sub>OL</sub>	-1.2	-0.8		V	5.0	T <sub>A</sub> = 25°C (Note 1)
V <sub>OHV</sub>	Minimum High Level Dynamic Output Voltage	2.5	3.0		V	5.0	T <sub>A</sub> = 25° (Note 3)
V <sub>IHD</sub>	Minimum High Level Dynamic Input Voltage	2.0	1.7		V	5.0	T <sub>A</sub> = 25°C (Note 2)
V <sub>ILD</sub>	Maximum Low Level Dynamic Input Voltage		0.7	0.9	V	5.0	T <sub>A</sub> = 25°C (Note 2)

**Note 1:** Max number of outputs defined as (n). n - 1 data inputs are driven 0V to 3V. One output at LOW. Guaranteed, but not tested.

**Note 2:** Max number of data inputs (n) switching. n - 1 inputs switching 0V to 3V. Input-under-test switching: 3V to threshold (V<sub>ILD</sub>), 0V to threshold (V<sub>IHD</sub>). Guaranteed, but not tested.

**Note 3:** Max number of outputs defined as (n). n - 1 data inputs are driven 0V to 3V. One output HIGH. Guaranteed, but not tested.

## AC Electrical Characteristics (SOIC and SSOP Packages): See Section 2 for Waveforms

Symbol	Parameter	74ABT			54ABT		74ABT		Units	Fig. No.
		T <sub>A</sub> = +25°C V <sub>CC</sub> = +5.0V C <sub>L</sub> = 50 pF			T <sub>A</sub> = -55°C to +125°C V <sub>CC</sub> = 4.5V-5.5V C <sub>L</sub> = 50 pF		T <sub>A</sub> = -40°C to +85°C V <sub>CC</sub> = 4.5V-5.5V C <sub>L</sub> = 50 pF			
		Min	Typ	Max	Min	Max	Min	Max		
t <sub>PLH</sub>	Propagation Delay	1.5		4.8	1.6	6.4	1.5	4.8	ns	2-3, 5
t <sub>PHL</sub>	A <sub>n</sub> to B <sub>n</sub> or B <sub>n</sub> to A <sub>n</sub>	1.5		4.8	1.6	6.2	1.5	4.8		
t <sub>PLH</sub>	Propagation Delay								ns	2-3, 5
t <sub>PHL</sub>	LEAB to B <sub>n</sub> , LEBA to A <sub>n</sub> OEBA or OEAB to A <sub>n</sub> or B <sub>n</sub>	1.6 1.6	3.4	5.3 5.3	1.6 1.6	6.6 6.4	1.6 1.6	5.3 5.3		
t <sub>PZH</sub>	Enable Time								ns	2-4
t <sub>PZL</sub>	LEAB to B <sub>n</sub> , LEBA to A <sub>n</sub> OEBA or OEAB to A <sub>n</sub> or B <sub>n</sub>	1.5 1.5	3.6	5.8 5.8	1.3 1.8	6.4 7.4	1.5 1.5	5.8 5.8		
t <sub>PHZ</sub>	Disable Time	2.0		6.5	2.0	7.2	2.0	6.5	ns	2-4
t <sub>PLZ</sub>	CEBA or CEAB to A <sub>n</sub> or B <sub>n</sub>	2.0	4.0	6.5	1.5	7.0	2.0	6.5		

## AC Operating Requirements (SOIC and SSOP Packages): See Section 2 for Waveforms

Symbol	Parameter	74ABT		54ABT		74ABT		Units	Fig. No.
		$T_A = +25^{\circ}\text{C}$ $V_{CC} = +5.0\text{V}$ $C_L = 50\text{ pF}$		$T_A = -55^{\circ}\text{C to } +125^{\circ}\text{C}$ $V_{CC} = 4.5\text{V}-5.5\text{V}$ $C_L = 50\text{ pF}$		$T_A = -40^{\circ}\text{C to } +85^{\circ}\text{C}$ $V_{CC} = 4.5\text{V}-5.5\text{V}$ $C_L = 50\text{ pF}$			
		Min	Max	Min	Max	Min	Max		
$t_{S(H)}$ $t_{S(L)}$	Setup Time, HIGH or LOW $A_n$ or $B_n$ to $\overline{LEBA}$ or $\overline{LEAB}$	1.5 1.5		3.5 3.0		1.5 1.5		ns	2-6
$t_{H(H)}$ $t_{H(L)}$	Hold Time, HIGH or LOW $A_n$ or $B_n$ to $\overline{LEBA}$ or $\overline{LEAB}$	1.0 1.0		2.0 2.0		1.0 1.0		ns	2-6
$t_{S(H)}$ $t_{S(L)}$	Setup Time, HIGH or LOW $A_n$ or $B_n$ to $\overline{CEAB}$ or $\overline{CEBA}$	1.5 1.5		3.3 2.5		1.5 1.5		ns	2-6
$t_{H(H)}$ $t_{H(L)}$	Hold Time, HIGH or LOW $A_n$ or $B_n$ to $\overline{CEAB}$ or $\overline{CEBA}$	1.3 1.3		2.0 2.0		1.3 1.3		ns	2-6
$t_W(L)$	Pulse Width, LOW	3.0		3.5		3.0		ns	2-3

## Extended AC Electrical Characteristics (SOIC Package): See Section 2

Symbol	Parameter	74ABT			74ABT			74ABT			Units	Fig. No.
		$T_A = -40^{\circ}\text{C to } +85^{\circ}\text{C}$ $V_{CC} = 4.5\text{V}-5.5\text{V}$ $C_L = 50\text{ pF}$ 8 Outputs Switching (Note 4)			$T_A = -40^{\circ}\text{C to } +85^{\circ}\text{C}$ $V_{CC} = 4.5\text{V}-5.5\text{V}$ $C_L = 250\text{ pF}$ 1 Output Switching (Note 5)			$T_A = -40^{\circ}\text{C to } +85^{\circ}\text{C}$ $V_{CC} = 4.5\text{V}-5.5\text{V}$ $C_L = 250\text{ pF}$ 8 Outputs Switching (Note 6)				
		Min	Typ	Max	Min	Max	Min	Max	Min	Max		
f <sub>toggle</sub>	Max Toggle Frequency	100									MHz	
t <sub>PLH</sub>	Propagation Delay	1.5		6.2	2.0	7.5		2.5	10.0		ns	2-3, 5
t <sub>PHL</sub>	A <sub>n</sub> to B <sub>n</sub> or B <sub>n</sub> to A <sub>n</sub>	1.5		6.2	2.0	7.5		2.5	10.0			
t <sub>PLH</sub>	Propagation Delay	1.5		6.5	2.0	8.0		2.5	10.5		ns	2-3, 5
t <sub>PHL</sub>	LEAB to B <sub>n</sub> , LEBA to A <sub>n</sub>	1.5		6.5	2.0	8.0		2.5	10.5			
t <sub>PZH</sub>	Output Enable Time										ns	2-4
t <sub>PZL</sub>	OEBA or OEAB to A <sub>n</sub> or B <sub>n</sub>	1.5		7.5	2.0	8.5		2.5	11.0			
	CEBA or CEAB to A <sub>n</sub> or B <sub>n</sub>	1.5		7.5	2.0	8.5		2.5	11.0			
t <sub>PHZ</sub>	Output Disable Time										ns	2-4
t <sub>PLZ</sub>	OEBA or OEAB to A <sub>n</sub> or B <sub>n</sub>	1.5		8.5	(Note 7)			(Note 7)				
	CEBA or CEAB to A <sub>n</sub> or B <sub>n</sub>	1.5		8.5								

**Note 4:** This specification is guaranteed but not tested. The limits apply to propagation delays for all paths described switching in phase (i.e., all low-to-high, high-to-low, etc.).

**Note 5:** This specification is guaranteed but not tested. The limits represent propagation delay with 250 pF load capacitors in place of the 50 pF load capacitors in the standard AC load. This specification pertains to single output switching only.

**Note 6:** This specification is guaranteed but not tested. The limits represent propagation delays for all paths described switching in phase (i.e., all low-to-high, high-to-low, etc.) with 250 pF load capacitors in place of the 50 pF load capacitors in the standard AC load.

**Note 7:** The TRI-STATE delay times are dominated by the RC network (500 $\Omega$ , 250 pF) on the output and has been excluded from the datasheet

**Skew** (SOIC Package): See Section 2

Symbol	Parameter	74ABT	74ABT	Units	Fig. No.
		$T_A = -40^{\circ}\text{C to } +85^{\circ}\text{C}$ $V_{CC} = 4.5\text{V} - 5.5\text{V}$ $C_L = 50\text{ pF}$ <b>8 Outputs Switching</b> <b>(Note 3)</b>	$T_A = -40^{\circ}\text{C to } +85^{\circ}\text{C}$ $V_{CC} = 4.5\text{V} - 5.5\text{V}$ $C_L = 250\text{ pF}$ <b>8 Outputs Switching</b> <b>(Note 4)</b>		
		Max	Max		
$t_{OSHL}$ (Note 1)	Pin to Pin Skew HL Transitions	1.0	2.0	ns	2-13
$t_{OSLH}$ (Note 1)	Pin to Pin Skew LH Transitions	1.3	2.0	ns	2-13
$t_{PS}$ (Note 5)	Duty Cycle LH-HL Skew	2.0	4.0	ns	2-14
$t_{OST}$ (Note 1)	Pin to Pin Skew LH/HL Transitions	2.0	4.0	ns	2-17
$t_{PV}$ (Note 2)	Device to Device Skew LH/HL Transitions	2.5	4.5	ns	2-20

**Note 1:** Skew is defined as the absolute value of the difference between the actual propagation delays for any two separate outputs of the same device. The specification applies to any outputs switching HIGH to LOW ( $t_{OSHL}$ ), LOW to HIGH ( $t_{OSLH}$ ), or any combination switching LOW to HIGH and/or HIGH to LOW ( $t_{OST}$ ). This specification is guaranteed but not tested.

**Note 2:** Propagation delay variation for a given set of conditions (i.e., temperature and  $V_{CC}$ ) from device to device. This specification is guaranteed but not tested.

**Note 3:** This specification is guaranteed but not tested. The limits apply to propagation delays for all paths described switching in phase (i.e., all LOW-to-HIGH, HIGH-to-LOW, etc.).

**Note 4:** This specification is guaranteed but not tested. The limits represent propagation delays with 250 pF load capacitors in place of the 50 pF load capacitors in the standard AC load.

**Note 5:** This describes the difference between the delay of the LOW-to-HIGH and the HIGH-to-LOW transition on the same pin. It is measured across all the outputs (drivers) on the same chip, the worst (largest delta) number is the guaranteed specification. This specification is guaranteed but not tested.

**Capacitance**

Symbol	Parameter	Typ	Units	Conditions: $T_A = 25^{\circ}\text{C}$
$C_{IN}$	Input Capacitance	5.0	pF	$V_{CC} = 0\text{V}$ (non I/O pins)
$C_{I/O}$ (Note 1)	Output Capacitance	11.0	pF	$V_{CC} = 5.0\text{V}$ ( $A_n$ , $B_n$ )

**Note 1:**  $C_{I/O}$  is measured at frequency,  $f = 1\text{ MHz}$ , PER MLT-STD-883B, METHOD 3012.